



1. General description

The TJA1057 is part of the Mantis family of high-speed CAN transceivers. It provides an interface between a Controller Area Network (CAN) protocol controller and the physical two-wire CAN bus. The transceiver is designed for high-speed CAN applications in the automotive industry, providing the differential transmit and receive capability to (a microcontroller with) a CAN protocol controller.

The TJA1057 offers a feature set optimized for 12 V automotive applications, with significant improvements over first- and second-generation CAN transceivers from NXP, such as the TJA1050, and excellent ElectroMagnetic Compatibility (EMC) performance. The TJA1057 also displays ideal passive behavior to the CAN bus when the supply voltage is off.

A $V_{\rm IO}$ pin on the TJA1057GT(K)/3 variants allows for direct interfacing with 3.3 V and 5 V-supplied microcontrollers.

The TJA1057 implements the CAN physical layer as defined in the current ISO11898-2:2003 standard and the pending updated version of ISO11898-2:201x. The TJA1057T variant is specified for data rates up to 1 Mbit/s. Pending the release of ISO11898-2:201x including CAN FD, additional timing parameters are specified for the TJA1057GT(/3) and TJA1057GTK(/3) variants. This implementation enables reliable communication in the CAN FD fast phase at data rates up to 5 Mbit/s.

These features make the TJA1057 an excellent choice for HS-CAN networks that only require basic CAN functionality.

2. Features and benefits

2.1 General

- Fully ISO 11898-2:2003 compliant
- Optimized for use in 12 V automotive systems
- EMC performance satisfies 'Hardware Requirements for LIN, CAN and FlexRay Interfaces in Automotive Applications', Version 1.3, May 2012.
- V_{IO} option allows for direct interfacing with 3.3 V and 5 V-supplied microcontrollers
- Non-V_{IO} variants can interface with 3.3 V and 5 V-supplied microcontrollers, provided the microcontroller I/Os are 5 V tolerant.
- AEC-Q100 qualified
- Dark green product (halogen free and Restriction of Hazardous Substances (RoHS) compliant)
- Available in SO8 package and leadless HVSON8 package (3.0 mm × 3.0 mm) with improved Automated Optical Inspection (AOI) capability



2.2 Predictable and fail-safe behavior

- Functional behavior predictable under all supply conditions
- Transceiver disengages from bus when not powered (zero load)
- Transmit Data (TXD) dominant time-out function
- Internal biasing of TXD and S input pins

2.3 Protection

- High ESD handling capability on the bus pins (8 kV IEC and HBM)
- Bus pins protected against transients in automotive environments
- Undervoltage detection on pins V_{CC} and V_{IO}
- Thermally protected

2.4 TJA1057GT(/3)/TJA1057GTK(/3)

- Timing guaranteed for data rates up to 5 Mbit/s
- Improved TXD to RXD propagation delay of 210 ns

3. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{CC}	supply voltage		4.75	-	5.25	V
V _{IO}	supply voltage on pin V _{IO}		2.95	-	5.25	V
V _{uvd(VCC)}	undervoltage detection voltage on pin V_{CC}		3.5	4	4.3	V
V _{uvd(VIO)}	undervoltage detection voltage on pin V_{IO}		2.1	-	2.8	V
I _{CC}	supply current	Silent mode	0.1	-	1.2	mA
		Normal mode; bus recessive	2	5	10	mA
		Normal mode; bus dominant	20	45	70	mA
I _{IO}	supply current on pin V _{IO}	Silent mode	-	3	16	μA
		Normal mode				
		recessive; $V_{TXD} = V_{IO}$	-	7	30	μA
		dominant; V _{TXD} = 0 V	-	110	320	μA
V _{ESD}	electrostatic discharge voltage	IEC 61000-4-2 at pins CANH and CANL	-8	-	+8	kV
V _{CANH}	voltage on pin CANH	limiting value according to IEC60134	-42	-	+42	V
V _{CANL}	voltage on pin CANL	limiting value according to IEC60134	-42	-	+42	V
T _{vi}	virtual junction temperature		-40	-	+150	°C

TJA1057

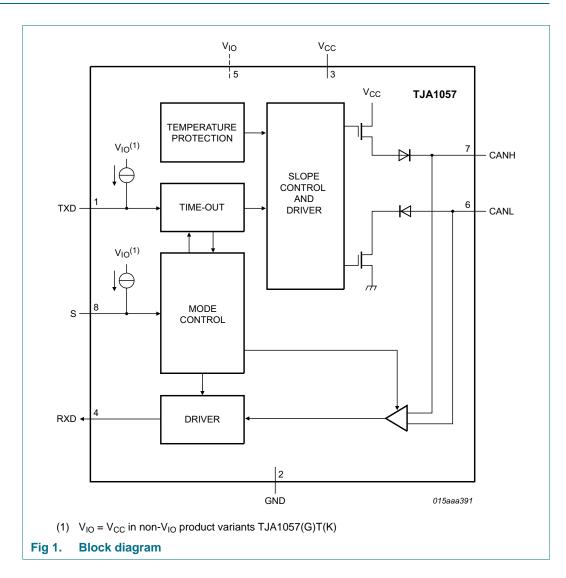
4. Ordering information

Table 2.	Ordering information	
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Type number	Package					
	Name	Description	Version			
TJA1057T	SO8	plastic small outline package; 8 leads; body width 3.9 mm	SOT96-1			
TJA1057GT						
TJA1057GT/3[1]						
TJA1057GTK	HVSON8	plastic thermal enhanced very thin small outline package; no leads;	SOT782-1			
TJA1057GTK/3[1]		8 terminals; body $3 \times 3 \times 0.85$ mm				

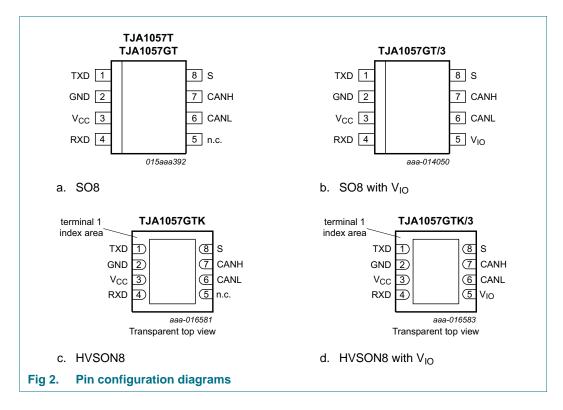
[1] TJA1057GT/3 and TJA1057GTK/3 variants have a V_{IO} pin.

5. Block diagram



6. Pinning information

6.1 Pinning



6.2 Pin description

Table 3.Pin description

Symbol	Pin	Description
TXD	1	transmit data input
GND ^[1]	2	ground
V _{CC}	3	supply voltage
RXD	4	receive data output; reads out data from the bus lines
n.c.	5	not connected in TJA1057T, TJA1057GT and TJA1057GTK
V _{IO}	5	supply voltage for I/O level adapter in TJA1057GT/3 and TJA1057GTK/3
CANL	6	LOW-level CAN bus line
CANH	7	HIGH-level CAN bus line
S	8	Silent mode control input

[1] HVSON8 package die supply ground is connected to both the GND pin and the exposed center pad. The GND pin must be soldered to board ground. For enhanced thermal and electrical performance, it is recommended that the exposed center pad also be soldered to board ground.

7. Functional description

7.1 Operating modes

The TJA1057 supports two operating modes, Normal and Silent. The operating mode is selected via pin S. See <u>Table 4</u> for a description of the operating modes under normal supply conditions.

Table 4.	Operating r	nodes

Mode	Inputs		Outputs				
	Pin S	Pin TXD	CAN driver	Pin RXD			
Normal	LOW	LOW	dominant	LOW			
		HIGH	recessive	LOW when bus dominant			
				HIGH when bus recessive			
Silent	HIGH	x ^[1]	biased to recessive	LOW when bus dominant			
				HIGH when bus recessive			

[1] x' = don't care.

7.1.1 Normal mode

A LOW level on pin S selects Normal mode. In this mode, the transceiver can transmit and receive data via the bus lines, CANH and CANL (see <u>Figure 1</u> for the block diagram). The differential receiver converts the analog data on the bus lines into digital data which is output on pin RXD. The slopes of the output signals on the bus lines are controlled internally and are optimized in a way that guarantees the lowest possible EME.

7.1.2 Silent mode

A HIGH level on pin S selects Silent mode. The transmitter is disabled in Silent mode, releasing the bus pins to recessive state. All other IC functions, including the receiver, continue to operate as in Normal mode. Silent mode can be used to prevent a faulty CAN controller disrupting all network communications.

7.2 Fail-safe features

7.2.1 TXD dominant time-out function

A 'TXD dominant time-out' timer is started when pin TXD is set LOW. If the LOW state on this pin persists for longer than $t_{to(dom)TXD}$, the transmitter is disabled, releasing the bus lines to recessive state. This function prevents a hardware and/or software application failure from driving the bus lines to a permanent dominant state (blocking all network communications). The TXD dominant time-out timer is reset when pin TXD is set HIGH. The TXD dominant time-out time also defines the minimum possible bit rate of approximately 25 kbit/s.

7.2.2 Internal biasing of TXD and S input pins

Pins TXD and S have internal pull-ups to V_{CC} (or V_{IO} in TJA1057GT(K)/3 variants) to ensure a safe, defined state in case one or both of these pins are left floating. Pull-up currents flow in these pins in all states; both pins should be held HIGH in Silent mode to minimize supply current.

7.2.3 Undervoltage detection on pins V_{CC} and V_{IO} (TJA1057GT(K)/3)

If V_{CC} or V_{IO} drops below the undervoltage detection level, V_{uvd(VCC)}/V_{uvd(VIO)}, the transceiver switches off and disengages from the bus (zero load; bus pins floating) until the supply voltage has recovered. The output drivers are enabled once both V_{CC} and V_{IO} are again within their operating ranges and TXD has been reset to HIGH.

7.2.4 Overtemperature protection

The output drivers are protected against overtemperature conditions. If the virtual junction temperature exceeds the shutdown junction temperature, $T_{j(sd)}$, both output drivers are disabled. When the virtual junction temperature drops below $T_{j(sd)}$ again, the output drivers recover once TXD has been reset to HIGH (waiting for TXD to go HIGH prevents output driver oscillation due to small variations in temperature).

7.2.5 V_{IO} supply pin (TJA1057GT(K)/3 variants only)

Pin V_{IO} should be connected to the microcontroller supply voltage (see <u>Figure 6</u>). The signal levels on pins TXD, RXD and S will then be adjusted to the I/O levels of the microcontroller, allowing for direct interfacing without additional glue logic.

For versions of the TJA1057 without a V_{IO} pin, the V_{IO} input is internally connected to V_{CC}. The signal levels of pins TXD, RXD and S are set to levels compatible with 5 V microcontrollers.

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). All voltages are referenced to GND.

Symbol	Parameter	Conditions		Min	Max	Unit
V _x	voltage on pin x	on pins CANH, CANL		-42	+42	V
		on pins V_{CC} , V_{IO}		-0.3	+7	V
		on any other pin	[1]	-0.3	V _{IO} [2] + 0.3	V
V _{(CANH} -CANL)	voltage between pin CANH and pin CANL			–15	+15	V
V _{trt}	transient voltage	on pins CANH, CANL	[3]			
		pulse 1		-100	-	V
		pulse 2a		-	75	V
		pulse 3a		-150	-	V
		pulse 3b		-	100	V
V _{ESD}	electrostatic discharge voltage	IEC 61000-4-2 (150 pF, 330 Ω)	<u>[4]</u>			
		on pins CANH and CANL		-8	+8	kV
		Human Body Model (HBM); 100 pF, 1.5 k Ω	[5]			
		on pins CANH and CANL		-8	+8	kV
		on any other pin		-4	+4	kV
		Machine Model (MM); 200 pF, 0.75 $\mu\text{H},$ 10 Ω	[6]			
		on any pin		-200	+200	V
		Charged Device Model (CDM); field Induced charge; 4 pF	[7]			
		on corner pins		-750	+750	V
		on any other pin		-500	+500	V
T _{vj}	virtual junction temperature		[8]	-40	+150	°C
T _{stg}	storage temperature			-55	+150	°C

[1] Maximum voltage should never exceed 7 V.

- [2] V_{IO} + 0.3 = V_{CC} + 0.3 in the non- V_{IO} product variants TJA1057(G)T(K).
- [3] According to IEC TS 62228 (2007), Section 4.2.4; parameters for standard pulses defined in ISO7637 part 2: 2004-06.
- [4] According to IEC TS 62228 (2007), Section 4.3; DIN EN 61000-4-2.

[5] According to AEC-Q100-002.

[6] According to AEC-Q100-003.

- [7] According to AEC-Q100-011; grade C3B.
- [8] In accordance with IEC 60747-1. An alternative definition of virtual junction temperature is: $T_{vj} = T_{amb} + P \times R_{th(vj-a)}$, where $R_{th(vj-a)}$ is a fixed value to be used for the calculation of T_{vj} . The rating for T_{vj} limits the allowable combinations of power dissipation (P) and ambient temperature (T_{amb}).

9. Thermal characteristics

Table 6. Thermal characteristics

According to IEC 60747-1.

Symbol	Parameter	Conditions	Value	Unit
	SO8 package; in free air	97	K/W	
	to ambient	HVSON8 package; in free air		
	dual-layer board [1]	91	K/W	
	four-layer board [2]	52	K/W	

[1] According to JEDEC JESD51-2, JESD51-3 and JESD51-5 at natural convection on 1s board with thermal via array under the exposed pad connected to the second copper layer.

[2] According to JEDEC JESD51-2, JESD51-5 and JESD51-7 at natural convection on 2s2p board. Board with two inner copper layers (thickness: 35 μm) and thermal via array under the exposed pad connected to the first inner copper layer.

10. Static characteristics

Table 7. Static characteristics

 $T_{vj} = -40$ °C to +150 °C; $V_{CC} = 4.75$ V to 5.25 V; $V_{IO} = 2.95$ V to 5.25 V[1]; $R_L = 60 \Omega$; $C_L = 100 \text{ pF}$ unless specified otherwise; All voltages are defined with respect to ground. Positive currents flow into the IC.[2]

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Supply; pi	n V _{CC}		I			
V _{CC}	supply voltage		4.75	-	5.25	V
V _{uvd(VCC)}	undervoltage detection voltage on pin V_{CC}		3.5	4	4.3	V
I _{CC}	supply current	Silent mode; $V_{TXD} = V_{IO}^{[3]}$	0.1	-	1.2	mA
		Normal mode				
		recessive; $V_{TXD} = V_{IO}^{[3]}$	2	5	10	mA
		dominant; V _{TXD} = 0 V	20	45	70	mA
I/O level a	dapter supply; pin V _{IO} [1]		L			
V _{IO}	supply voltage on pin V _{IO}		2.95	-	5.25	V
V _{uvd(VIO)}	undervoltage detection voltage on pin V_{IO}		2.1	-	2.8	V
I _{IO}	supply current on pin V _{IO}	Silent mode	-	3	16	μA
		Normal mode				
		recessive; $V_{TXD} = V_{IO}$	-	7	30	μA
		dominant; V _{TXD} = 0 V	-	110	320	μA
Silent mod	le control input; pin S					
V _{IH}	HIGH-level input voltage		2	-	V _{IO} [3] + 0.3	V
V _{IL}	LOW-level input voltage		-0.3	-	0.8	V
I _{IH}	HIGH-level input current	$V_{S} = V_{IO}^{[3]}$	-1	-	+1	μA
I _{IL}	LOW-level input current	$V_{S} = 0 V$	-15	-	-1	μA
CAN trans	mit data input; pin TXD		I			
V _{IH}	HIGH-level input voltage		2	-	V _{IO} [3] + 0.3	V
V _{IL}	LOW-level input voltage		-0.3	-	0.8	V
I _{IH}	HIGH-level input current	$V_{TXD} = V_{IO}^{[3]}$	-5	-	+5	μA

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Table 7. Static characteristics ...continued

 $T_{vj} = -40 \ ^{\circ}C$ to $+150 \ ^{\circ}C$; $V_{CC} = 4.75 \ V$ to 5.25 V; $V_{IO} = 2.95 \ V$ to 5.25 V^[1]; $R_L = 60 \ \Omega$; $C_L = 100 \ pF$ unless specified otherwise; All voltages are defined with respect to ground. Positive currents flow into the IC.^[2]

Unit	Max	Тур	Min	Conditions	Parameter	Symbol
μA	-30	-	-260	V _{TXD} = 0 V	LOW-level input current	IIL
pF	10	5	-	[4]	input capacitance	C _i
				1	data output; pin RXD	CAN receive
mA	-1	-3	-8	$V_{RXD} = V_{IO}^{[3]} - 0.4 V$	HIGH-level output current	I _{OH}
mA	12	-	1	V _{RXD} = 0.4 V; bus dominant	LOW-level output current	I _{OL}
	-		1		ns CANH and CANL	Bus lines; pi
				$V_{TXD} = 0 V; t < t_{to(dom)TXD}$	dominant output voltage	V _{O(dom)}
V	4.5	3.5	2.75	pin CANH; $R_L = 50 \Omega$ to 65 Ω		
V	2.25	1.5	0.5	pin CANL; $R_L = 50 \Omega$ to 65Ω		
mV	+400	-	-400	$V_{dom(TX)sym} = V_{CC} - V_{CANH} - V_{CANL}$	transmitter dominant voltage symmetry	V _{dom(TX)} sym
V	1.1V _{CC}	-	0.9V _{CC}	$V_{TXsym} = V_{CANH} + V_{CANL}; \qquad [4] \\ f_{TXD} = 250 \text{ kHz}; C_{SPLIT} = 4.7 \text{ nF} \qquad [5]$	transmitter voltage symmetry	V _{TXsym}
V	3	-	1.5		differential output voltage	V _{O(dif)}
V	3	-	1.4			
V	5	-	1.5			
mV	+50	-	-50	$V_{TXD} = V_{IO}$ recessive; no load		
V	3	$0.5V_{CC}$	2	$V_{TXD} = V_{IO}^{[3]}$; no load	recessive output voltage	V _{O(rec)}
V	0.9	-	0.5	Normal/Silent mode; $-12 V \le V_{CANL} \le +12 V;$ $-12 V \le V_{CANH} \le +12 V$	differential receiver threshold voltage	V _{th(RX)dif}
V	0.5	-	-3	Normal/Silent mode; $-12 V \le V_{CANL} \le +12 V;$ $-12 V \le V_{CANH} \le +12 V$	receiver recessive voltage	V _{rec(RX)}
V	8.0	-	0.9	Normal/Silent mode; $-12 V \le V_{CANL} \le +12 V;$ $-12 V v V_{CANH} \le +12 V$	receiver dominant voltage	V _{dom(RX)}
mV	300	-	50	Normal mode; $-12 V \le V_{CANL} \le +12 V;$ $-12 V v V_{CANH} \le +12 V$	differential receiver hysteresis voltage	V _{hys(RX)} dif
				$V_{TXD} = 0 V; t < t_{to(dom)TXD}; V_{CC} = 5 V$	dominant short-circuit output	I _{O(sc)dom}
mA	-40	-70	-100	pin CANH; $V_{CANH} = -3 V$ to 18 V	current	
mA	100	70	40	pin CANL; $V_{CANL} = -3 V$ to 40 V		
mA	+5	-	-5	Normal mode; $V_{TXD} = V_{CC}$ $V_{CANH} = V_{CANL} = -27$ V to +32 V	recessive short-circuit output current	I _{O(sc)rec}
μA	+5	-	-5	$V_{CC} = 0 V \text{ or } V_{CC} \text{ shorted to GND}$ via 47 k Ω ; $V_{CANH} = V_{CANL} = 5 V$	leakage current	IL
kΩ	28	15	9		input resistance	R _i
%	+3	-	-3	between V_{CANH} and V_{CANL}	input resistance deviation	ΔR _i
kΩ	52	30	19		differential input resistance	R _{i(dif)}
	28 +3	-	9 3	via 47 k Ω ; V _{CANH} = V _{CANL} = 5 V	input resistance input resistance deviation	IL Ri ΔRi Ri(dif)

Table 7. Static characteristics ...continued

 $T_{vj} = -40 \ ^{\circ}C$ to +150 $^{\circ}C$; $V_{CC} = 4.75 \ V$ to 5.25 V; $V_{IO} = 2.95 \ V$ to 5.25 V^[1]; $R_L = 60 \ \Omega$; $C_L = 100 \ pF$ unless specified otherwise; All voltages are defined with respect to ground. Positive currents flow into the IC.^[2]

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
C _{i(cm)}	common-mode input capacitance	[4]	-	-	20	pF
C _{i(dif)}	differential input capacitance	[4]	-	-	10	pF
Temperature	detection					
T _{j(sd)}	shutdown junction temperature	[4]	-	185	-	°C

[1] Only TJA1057GT/3 and TJA1057GTK/3 have a V_{IO} pin; the V_{IO} input is internally connected to V_{CC} in the other variants.

[2] Factory testing uses correlated test conditions to cover the specified temperature and power supply voltage range.

[3] $V_{IO} = V_{CC}$ in non-V_{IO} product variants TJA1057(G)T(K).

[4] Not tested in production; guaranteed by design.

[5] The test circuit used to measure the bus output voltage symmetry (which includes C_{SPLIT}) is shown in Figure 8.

11. Dynamic characteristics

Table 8. Dynamic characteristics

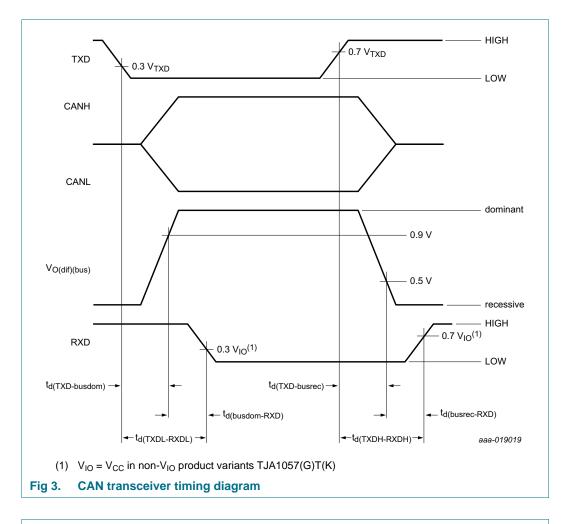
 $T_{vj} = -40 \text{ °C to} + 150 \text{ °C}; V_{CC} = 4.75 \text{ V to} 5.25 \text{ V}; V_{IO} = 2.95 \text{ V to} 5.25 \text{ V}^{11}; R_L = 60 \Omega; C_L = 100 \text{ pF}$ unless specified otherwise. All voltages are defined with respect to ground.^[2]

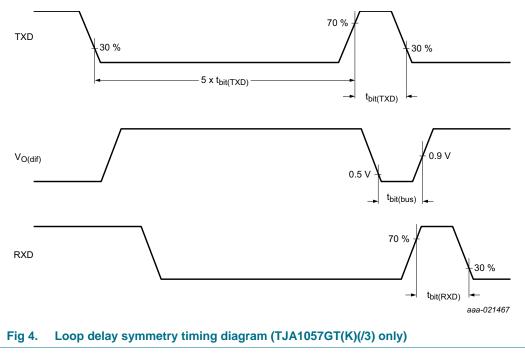
Parameter	Conditions	Min	Тур	Max	Unit
iming; pins CANH, CANL, TXD and RXD	; see <mark>Figure 7</mark> and <mark>Figure 3</mark>				
delay time from TXD to bus dominant	Normal mode	-	65	-	ns
delay time from TXD to bus recessive	Normal mode	-	90	-	ns
delay time from bus dominant to RXD	Normal mode	-	60	-	ns
delay time from bus recessive to RXD	Normal mode	-	65	-	ns
delay time from TXD LOW to RXD LOW	TJA1057T; Normal mode	50	-	230	ns
	TJA1057GT(/3), TJA1057GTK(/3); Normal mode	50	-	210	ns
delay time from TXD HIGH to RXD HIGH	TJA1057T; Normal mode	50	-	230	ns
	TJA1057GT(/3), TJA1057GTK(/3); Normal mode	50	-	210	ns
transmitted recessive bit width	TJA1057GT(/3), TJA1057GTK(/3)				
	t _{bit(TXD)} = 500 ns	435	-	530	ns
	t _{bit(TXD)} = 200 ns	155	-	210	ns
bit time on pin RXD	TJA1057GT(/3), TJA1057GTK(/3)				
	t _{bit(TXD)} = 500 ns [3]	400	-	550	ns
	t _{bit(TXD)} = 200 ns [3]	120	-	220	ns
receiver timing symmetry	TJA1057GT(/3), TJA1057GTK(/3)				
	t _{bit(TXD)} = 500 ns	-65	-	+40	ns
	t _{bit(TXD)} = 200 ns	-45	-	+15	ns
TXD dominant time-out time	V _{TXD} = 0 V; Normal mode	0.8	3	6.5	ms
	iming; pins CANH, CANL, TXD and RXD delay time from TXD to bus dominant delay time from TXD to bus recessive delay time from bus dominant to RXD delay time from bus recessive to RXD delay time from TXD LOW to RXD LOW delay time from TXD HIGH to RXD HIGH transmitted recessive bit width bit time on pin RXD receiver timing symmetry	iming; pins CANH, CANL, TXD and RXD; see Figure 7 and Figure 3delay time from TXD to bus dominantNormal modedelay time from TXD to bus recessiveNormal modedelay time from bus dominant to RXDNormal modedelay time from bus recessive to RXDNormal modedelay time from TXD LOW to RXD LOWTJA1057T; Normal modedelay time from TXD LOW to RXD LOWTJA1057GT(/3), TJA1057GTK(/3); Normal modedelay time from TXD HIGH to RXD HIGHTJA1057GT(/3), TJA1057GTK(/3); Normal modedelay time from TXD HIGH to RXD HIGHTJA1057GT(/3), TJA1057GTK(/3); Normal modetransmitted recessive bit widthTJA1057GT(/3), TJA1057GTK(/3) tbit(TXD) = 500 ns tbit(TXD) = 200 nsbit time on pin RXDTJA1057GT(/3), TJA1057GTK(/3) tbit(TXD) = 200 nsreceiver timing symmetryTJA1057GT(/3), TJA1057GTK(/3) tbit(TXD) = 500 ns tbit(TXD) = 200 ns			$ \begin{array}{c c c c c c c c c c c c c c c c c c c $

[1] Only TJA1057GT/3 and TJA1057GTK/3 have a V_{IO} pin; the V_{IO} input is internally connected to V_{CC} in the other variants.

[2] Factory testing uses correlated test conditions to cover the specified temperature and power supply voltage range.

[3] See Figure 4.

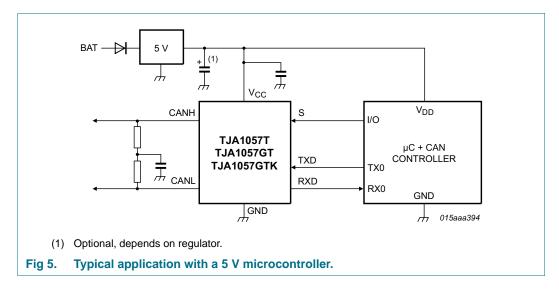


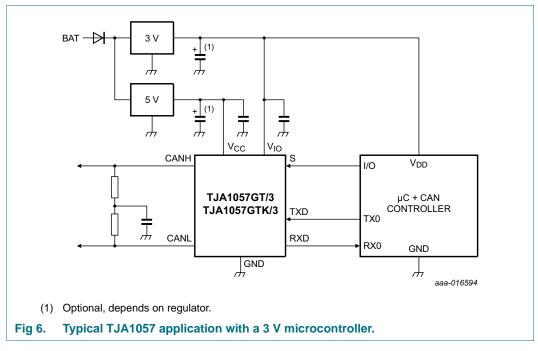


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12. Application information

12.1 Application diagram



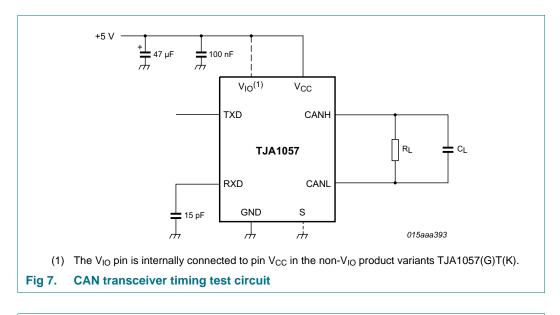


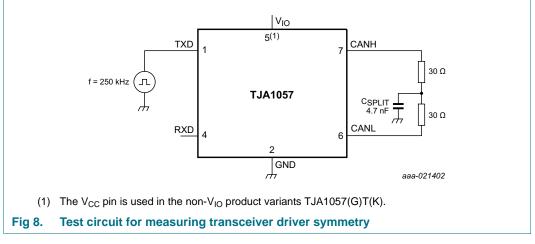
12.2 Application hints

Further information on the application of the TJA1057 can be found in NXP application hints *AH1308 Application Hints - Standalone high speed CAN transceiver Mantis-GT TJA1044G/TJA1057G.*

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13. Test information





13.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q100 Rev-G - Failure mechanism based stress test qualification for integrated circuits*, and is suitable for use in automotive applications.

14. Package outline

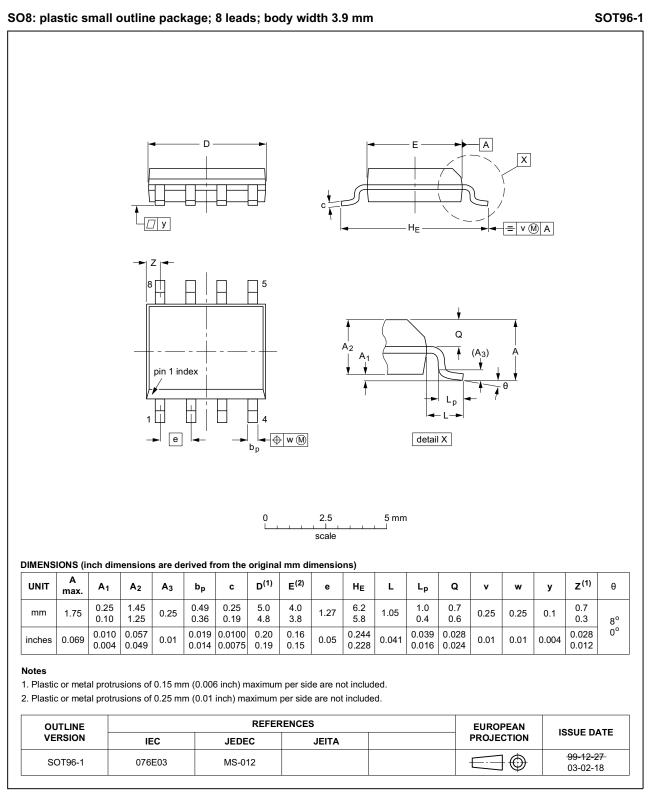
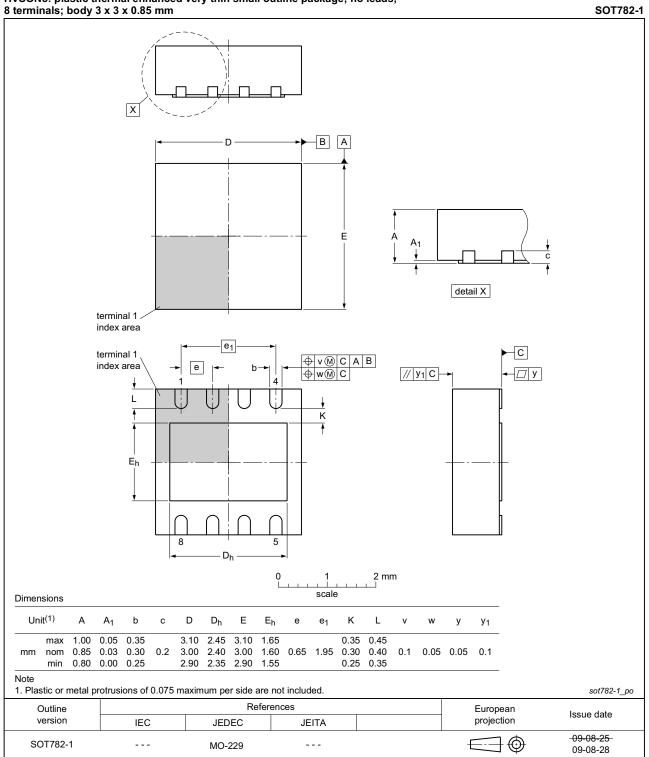


Fig 9. Package outline SOT96-1 (SO8)

TJA1057

Product data sheet



HVSON8: plastic thermal enhanced very thin small outline package; no leads;

Fig 10. Package outline SOT782-1 (HVSON8)

15. Handling information

All input and output pins are protected against ElectroStatic Discharge (ESD) under normal handling. When handling ensure that the appropriate precautions are taken as described in *JESD625-A* or equivalent standards.

16. Soldering of SMD packages

This text provides a very brief insight into a complex technology. A more in-depth account of soldering ICs can be found in Application Note *AN10365 "Surface mount reflow soldering description"*.

16.1 Introduction to soldering

Soldering is one of the most common methods through which packages are attached to Printed Circuit Boards (PCBs), to form electrical circuits. The soldered joint provides both the mechanical and the electrical connection. There is no single soldering method that is ideal for all IC packages. Wave soldering is often preferred when through-hole and Surface Mount Devices (SMDs) are mixed on one printed wiring board; however, it is not suitable for fine pitch SMDs. Reflow soldering is ideal for the small pitches and high densities that come with increased miniaturization.

16.2 Wave and reflow soldering

Wave soldering is a joining technology in which the joints are made by solder coming from a standing wave of liquid solder. The wave soldering process is suitable for the following:

- Through-hole components
- Leaded or leadless SMDs, which are glued to the surface of the printed circuit board

Not all SMDs can be wave soldered. Packages with solder balls, and some leadless packages which have solder lands underneath the body, cannot be wave soldered. Also, leaded SMDs with leads having a pitch smaller than ~0.6 mm cannot be wave soldered, due to an increased probability of bridging.

The reflow soldering process involves applying solder paste to a board, followed by component placement and exposure to a temperature profile. Leaded packages, packages with solder balls, and leadless packages are all reflow solderable.

Key characteristics in both wave and reflow soldering are:

- · Board specifications, including the board finish, solder masks and vias
- Package footprints, including solder thieves and orientation
- The moisture sensitivity level of the packages
- Package placement
- Inspection and repair
- Lead-free soldering versus SnPb soldering

16.3 Wave soldering

Key characteristics in wave soldering are:

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- Process issues, such as application of adhesive and flux, clinching of leads, board transport, the solder wave parameters, and the time during which components are exposed to the wave
- Solder bath specifications, including temperature and impurities

16.4 Reflow soldering

Key characteristics in reflow soldering are:

- Lead-free versus SnPb soldering; note that a lead-free reflow process usually leads to higher minimum peak temperatures (see <u>Figure 11</u>) than a SnPb process, thus reducing the process window
- Solder paste printing issues including smearing, release, and adjusting the process window for a mix of large and small components on one board
- Reflow temperature profile; this profile includes preheat, reflow (in which the board is heated to the peak temperature) and cooling down. It is imperative that the peak temperature is high enough for the solder to make reliable solder joints (a solder paste characteristic). In addition, the peak temperature must be low enough that the packages and/or boards are not damaged. The peak temperature of the package depends on package thickness and volume and is classified in accordance with <u>Table 9</u> and <u>10</u>

Table 9. SnPb eutectic process (from J-STD-020D)

Package thickness (mm)	Package reflow temperature (°C) Volume (mm ³)		
	< 350	≥ 350	
< 2.5	235	220	
≥ 2.5	220	220	

Table 10. Lead-free process (from J-STD-020D)

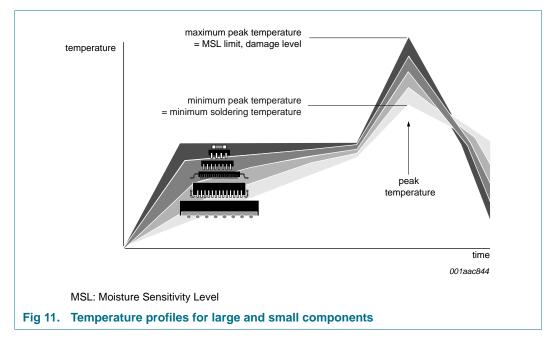
Package thickness (mm)	Package reflow temperature (°C) Volume (mm ³)		
	< 350	350 to 2000	> 2000
< 1.6	260	260	260
1.6 to 2.5	260	250	245
> 2.5	250	245	245

Moisture sensitivity precautions, as indicated on the packing, must be respected at all times.

Studies have shown that small packages reach higher temperatures during reflow soldering, see Figure 11.

High-speed CAN transceiver

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For further information on temperature profiles, refer to Application Note *AN10365* "Surface mount reflow soldering description".

17. Appendix: ISO 11898-2:201x parameter cross-reference list

Table 11. ISO 11898-2:201x to NXP data sheet parameter conversion

ISO 11898-2:201x	NXP data sheet		
Parameter	Notation	Symbol	Parameter
HS-PMA dominant output characteristics	1		
Single ended voltage on CAN_H	V _{CAN_H}	V _{O(dom)}	dominant output voltage
Single ended voltage on CAN_L	V _{CAN_L}		
Differential voltage on normal bus load	V _{Diff}	V _{O(dif)}	differential output voltage
Differential voltage on effective resistance during arbitration	=		
Optional: Differential voltage on extended bus load range	-		
HS-PMA driver symmetry			
Driver symmetry	V _{SYM}	V _{TXsym}	transmitter voltage symmetry
Maximum HS-PMA driver output current	1		
Absolute current on CAN_H	I _{CAN_H}	I _{O(sc)dom}	dominant short-circuit output
Absolute current on CAN_L	I _{CAN_L}	-	current
HS-PMA recessive output characteristics, bus biasing ac	tive/inacti	ve	
Single ended output voltage on CAN_H	V _{CAN_H}	V _{O(rec)}	recessive output voltage
Single ended output voltage on CAN_L	V _{CAN_L}		
Differential output voltage	V _{Diff}	V _{O(dif)}	differential output voltage
Optional HS-PMA transmit dominant timeout	1		
Transmit dominant timeout, long	t _{dom}	t _{to(dom)TXD}	TXD dominant time-out time
Transmit dominant timeout, short	-		
HS-PMA static receiver input characteristics, bus biasing	g active/ina	active	
Recessive state differential input voltage range Dominant state differential input voltage range	V _{Diff}	V _{th(RX)} dif	differential receiver threshold voltage
		V _{rec(RX)}	receiver recessive voltage
		V _{dom(RX)}	receiver dominant voltage
HS-PMA receiver input resistance (matching)			
Differential internal resistance	R _{Diff}	R _{i(dif)}	differential input resistance
Single ended internal resistance	R _{CAN_H} R _{CAN_L}	R _i	input resistance
Matching of internal resistance	MR	ΔR_i	input resistance deviation
HS-PMA implementation loop delay requirement			
Loop delay	t _{Loop}	t _{d(TXDH-RXDH)}	delay time from TXD HIGH to RXD HIGH
		$t_{d(TXDL-RXDL)}$	delay time from TXD LOW to RXD LOW
Optional HS-PMA implementation data signal timing requ 2 Mbit/s and above 2 Mbit/s up to 5 Mbit/s	lirements	for use with bit	rates above 1 Mbit/s up to
Transmitted recessive bit width @ 2 Mbit/s / @ 5 Mbit/s, intended	t _{Bit(Bus)}	t _{bit(bus)}	transmitted recessive bit width
Received recessive bit width @ 2 Mbit/s / @ 5 Mbit/s	t _{Bit(RXD)}	t _{bit(RXD)}	bit time on pin RXD
Receiver timing symmetry @ 2 Mbit/s / @ 5 Mbit/s	Δt_{Rec}	Δt_{rec}	receiver timing symmetry

Table 11. ISO 11898-2:201x to NXP data sheet parameter conversion

ISO 11898-2:201x		NXP data sheet		
Parameter	Notation	Symbol	Parameter	
HS-PMA maximum ratings of $V_{CAN_{-}H}$, $V_{CAN_{-}L}$ and V_{Diff}				
Maximum rating V _{Diff}	V _{Diff}	V _(CANH-CANL)	voltage between pin CANH and pin CANL	
General maximum rating $V_{\text{CAN}_{-}\text{H}}$ and $V_{\text{CAN}_{-}\text{L}}$	V _{CAN_H}	V _x	voltage on pin x	
Optional: Extended maximum rating VCAN_H and VCAN_L	V _{CAN_L}			
HS-PMA maximum leakage currents on CAN_H and CAN	L, unpow	ered		
Leakage current on CAN_H, CAN_L	I _{CAN_H} I _{CAN_L}	IL	leakage current	
HS-PMA bus biasing control timings				
CAN activity filter time, long	t _{Filter}	t _{wake(busdom)} [1]	bus dominant wake-up time	
CAN activity filter time, short		t _{wake(busrec)} [1]	bus recessive wake-up time	
Wake-up timeout, short	t _{Wake}	t _{to(wake)bus}	bus wake-up time-out time	
Wake-up timeout, long	1			
Timeout for bus inactivity	t _{Silence}	t _{to(silence)}	bus silence time-out time	
Bus Bias reaction time	t _{Bias}	t _{d(busact-bias)}	delay time from bus active to bias	

[1] t_{fltr(wake)bus} - bus wake-up filter time, in devices with basic wake-up functionality

18. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
TJA1057 v.5	20160128	Product data sheet	-	TJA1057 v.4
TJA1057 v.5 Modifications:	 TJA1057GT/3 and TJA <u>Section 1</u>: 3rd parage <u>Section 2.1</u>: feature <u>Section 2.3</u>: feature <u>Section 2.4</u>: heading amended <u>Table 1</u>, <u>Table 7</u>: parage <u>Table 2</u>: ordering inf <u>Figure 1</u>, <u>Figure 2</u>, <u>Figure 1</u>, <u>Figure 2</u>, and <u>Section 7.2.5</u> added <u>Section 7.2.5</u> added <u>Table 5</u>, <u>Table 7</u>, <u>Table 5</u>: parameter V <u>Table 5</u>: parameter V <u>Table 7</u>: measurement con removed), V_{hys(RX)dir} parameters V_{TXsyr} additional measure 	1057GTK/3 variants added: graph added added amended to include V_{IO} g amended to include TJA1057 rameters V_{IO} , $V_{uvd(VIO)}$ and I_{IO} a ormation updated Figure 3 and Table 3 amended; ection 7.2.3: text amended ble 8: measurement conditions pliance: nded (4th paragraph) $V_{(CANH-CANL)}$ added ditions changed for parameters f, $I_{O(sc)dom}$ and I_{L} n (and associated table note), N ement included for parameters N t _{bit(bus)} and Δt_{rec} added ind Figure 8 added vised n Silent mode) nded	added <u>Figure 6</u> added revised to include n s V _{O(dom)} , V _{th(RX)dif} (a V _{rec(RX)} and V _{dom(RX)}	GTK/3; text of 1st feature ew variants associated table note
	• <u>Table 7</u> : parameters $I_{O(dom)}$ and $I_{O(rec)}$ renamed as $I_{O(sc)dom}$ and $I_{O(sc)rec}$			
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TJA1057 v.4	20150710	Product data sheet	-	TJA1057 v.3
TJA1057 v.3	20141119	Product data sheet	-	TJA1057 v.2
TJA1057 v.2	20131030	Product data sheet	-	TJA1057 v.1
TJA1057 v.1	20130530	Preliminary data sheet	-	-

19. Legal information

19.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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